

P(Xi) is the same
$$\forall i \in \{1, ..., n\}$$

- id (indepent distribution)

Y:= Xi+2

> $\in \perp x_i$, $\in \sim N(0,1)$

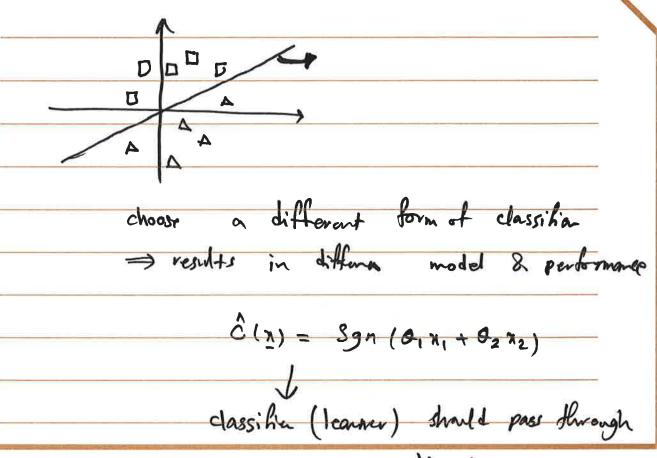
if X_i 's are iid, what is the distribution of Yi in given x_i are observed.

P(Y₁,..., Yn|X₁... Xn) = $\uparrow \uparrow P(Y_i \mid X_i)$

 $P(Y_i|X_i) \sim N(x_i, 1) \longrightarrow = \frac{1}{\sqrt{2n}} \exp(\frac{1}{2}(y_i-y_i)^2)$

identical for all i, but P(Yilki) are index. from each other VC dimension: we have I how complexity a model can affect the performance of the model heet to define complexity of model VC dimension can be used to define complexity. representation power is the ability of model to lear a wide variety of input-autal relationship of or ability to memorize to lit data Example: perceptron for 2D ê(n) = Sgn (0, n, + 02 22+ 0.)

p(Yilxi) is a function ni > it is Not



example: $c(x) = 8gn(x^{\frac{1}{2}} - 8.)$ Example: $c(x) = 8gn(x^{\frac{1}{2}} - 8.)$ If value of 11211 is large \rightarrow it values field as +1

otherwise $\rightarrow 11.11^2 + 11.11^$

the wave representation power we can have for classifier, the more account model on training data we have, but this is at the cost of evertiting

the less rep. power 1 poor putament on training

How we can we quantify representation power?

(VC dim.)

Let's have some preliminary on VC:

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- let's assume one training data are iid from

dist. p(n)

- let's define 'tisk" & "emperical risk"

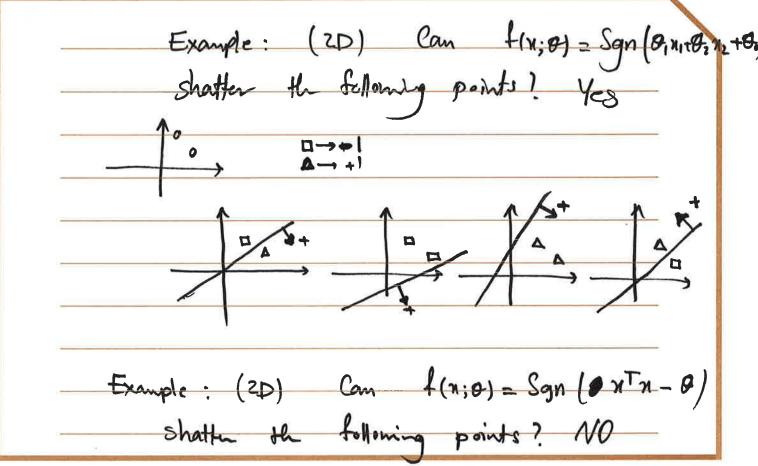
Those one just "long term" test &

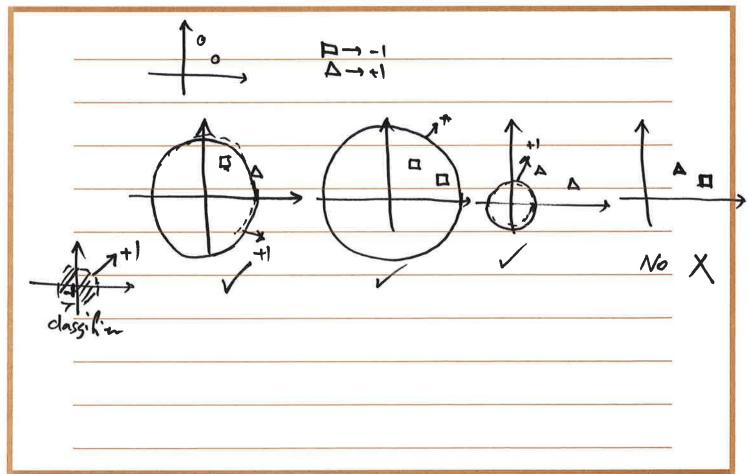
"observed" training errors

R(0) = Test Error = E(S(C + c(n; 0))

Remp(0) = Train Error = In S(c") + c(n");0))

Q: How one these errors related?
- under litting domain:
Test error is similar to train error
- over Litting domain:
testerror is be any worse!
VC dim. tells us about risk:
- Given some classition, let 4 be its vc
dim.
- with " high probl 1-y, it can be shown
Host
Test ever < Teach Ervor+ 1 H log (2m) + H - log 4 (m is # of training data)
H1 > overfitting
1 -> Test & Trains our similar
Shattering.
we say a classifier f/n) can shatter
points n(1) n(h) iff for all y(1)y(h)
f(n) can achieve vero error on training





VC dim:

The VC dim H is defined as

the maps. # of points h that

can be arranged so flot I(n) can

shatter all of them.

A game:

- fix the ded f(n;0)

- Player 1: chaose location of x(1)...x(h)

- " 2: " target labels of x(1)...x(h)

(y(1)...y(h))

if $f(n; \sigma)$ can reproduce the target labels,

player 1 wins

I $\chi(i)$ h

Sit. $\chi(i)$ h $\chi(i)$

